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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	12675
Number of Logic Elements/Cells	162240
Total RAM Bits	11980800
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	676-BBGA, FCBGA
Supplier Device Package	676-FCBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k160t-2ffg676c

Table 2: Recommended Operating Conditions ⁽¹⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
$V_{MGTAVTTRCAL}$ ⁽⁸⁾	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

Notes:

- All voltages are relative to ground.
- V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
- Configuration data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
- The lower absolute voltage specification always applies.
- A total of 200 mA per bank should not be exceeded.
- V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .
- Each voltage listed requires the filter circuit described in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#).
- For data rates ≤ 10.3125 Gb/s, $V_{MGTAVCC}$ should be $1.0V \pm 3\%$ for lower power consumption.
- For lower power consumption, $V_{MGTAVCC}$ should be $1.0V \pm 3\%$ over the entire CPLL frequency range.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	15	μA
I_L	Input or output leakage current per pin (sample-tested)	–	–	15	μA
C_{IN} ⁽²⁾	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 3.3V$	90	–	330	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 2.5V$	68	–	250	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.8V$	34	–	220	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.5V$	23	–	150	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$, $V_{CCO} = 1.2V$	12	–	120	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 3.3V$	68	–	330	μA
	Pad pull-down (when selected) @ $V_{IN} = 1.8V$	45	–	180	μA
I_{CCADC}	Analog supply current, analog circuits in powered up state	–	–	25	mA
I_{BATT} ⁽³⁾	Battery supply current	–	–	150	nA

Table 3: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
$R_{IN_TERM}^{(4)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_40) for commercial (C), industrial (I), and extended (E) temperature devices	28	40	55	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_50) for commercial (C), industrial (I), and extended (E) temperature devices	35	50	65	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_60) for commercial (C), industrial (I), and extended (E) temperature devices	44	60	83	Ω
n	Temperature diode ideality factor	—	1.010	—	—
r	Temperature diode series resistance	—	2	—	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. This measurement represents the die capacitance at the pad, not including the package.
3. Maximum value specified for worst case process at 25°C.
4. Termination resistance to a $V_{CCO}/2$ level.

Table 4: Maximum Allowed AC Voltage Overshoot and Undershoot for 3.3V HR I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI @–40°C to 100°C	AC Voltage Undershoot	% of UI @–40°C to 100°C
$V_{CCO} + 0.40$	100	–0.40	100
$V_{CCO} + 0.45$	100	–0.45	61.7
$V_{CCO} + 0.50$	100	–0.50	25.8
$V_{CCO} + 0.55$	100	–0.55	11.0
$V_{CCO} + 0.60$	46.6	–0.60	4.77
$V_{CCO} + 0.65$	21.2	–0.65	2.10
$V_{CCO} + 0.70$	9.75	–0.70	0.94
$V_{CCO} + 0.75$	4.55	–0.75	0.43
$V_{CCO} + 0.80$	2.15	–0.80	0.20
$V_{CCO} + 0.85$	1.02	–0.85	0.09
$V_{CCO} + 0.90$	0.49	–0.90	0.04
$V_{CCO} + 0.95$	0.24	–0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI @–40°C to 100°C	AC Voltage Undershoot	% of UI @–40°C to 100°C
$V_{CCO} + 0.40$	100	–0.40	100
$V_{CCO} + 0.45$	100	–0.45	100
$V_{CCO} + 0.50$	100	–0.50	100
$V_{CCO} + 0.55$	100	–0.55	100
$V_{CCO} + 0.60$	50.0	–0.60	50.0
$V_{CCO} + 0.65$	50.0	–0.65	50.0
$V_{CCO} + 0.70$	47.0	–0.70	50.0
$V_{CCO} + 0.75$	21.2	–0.75	50.0

LVDS DC Specifications (LVDS_25)

The LVDS_25 standard is available in the HR I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 12: LVDS_25 DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 13: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		1.710	1.800	1.890	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100\ \Omega$ across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.300	1.200	1.425	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in ISE® software 14.3 v1.07 for the -3, -2, -2L(1.0V), -1, and v1.06 for -2L(0.9V) speed grades.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Kintex-7 FPGAs.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 14](#) correlates the current status of each Kintex-7 device on a per speed grade basis.

Table 14: Kintex-7 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7K70T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K160T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K325T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K355T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K410T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K420T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K480T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

[Table 15](#) lists the production released Kintex-7 device, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 15: Kintex-7 Device Production Software and Speed Specification Release

Device	Speed Grade Designations			
	1.0V			0.9V
	-3	-2/-2L	-1	-2L
XC7K70T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K160T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K325T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K355T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K410T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K420T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K480T	ISE 14.2 v1.06			ISE 14.3 v1.06

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Kintex-7 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 11](#). In each table, the I/O bank type is either High Performance (HP) or High Range (HR).

Table 16: Networking Applications Interface Performances

Description	I/O Bank Type	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	HR	710	710	625	625	Mb/s
	HP	710	710	625	625	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	HR	1250	1250	950	950	Mb/s
	HP	1600	1400	1250	1250	Mb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	HR	710	710	625	625	Mb/s
	HP	710	710	625	625	Mb/s
DDR LVDS receiver (SFI-4.2) ⁽¹⁾	HR	1250	1250	950	950	Mb/s
	HP	1600	1400	1250	1250	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVTTTL_S4	1.31	1.42	1.64	1.51	5.27	5.63	6.05	4.13	6.03	6.49	7.04	4.64	ns
LVTTTL_S8	1.31	1.42	1.64	1.51	4.45	4.83	5.30	3.86	5.21	5.69	6.29	4.38	ns
LVTTTL_S12	1.31	1.42	1.64	1.51	4.45	4.83	5.29	3.84	5.21	5.69	6.28	4.36	ns
LVTTTL_S16	1.31	1.42	1.64	1.51	3.47	3.88	4.40	3.39	4.23	4.74	5.39	3.91	ns
LVTTTL_S24	1.31	1.42	1.64	1.51	3.58	3.99	4.51	3.61	4.34	4.85	5.50	4.13	ns
LVTTTL_F4	1.31	1.42	1.64	1.51	4.70	4.98	5.29	3.58	5.46	5.84	6.28	4.09	ns
LVTTTL_F8	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.06	4.42	4.92	5.55	3.58	ns
LVTTTL_F12	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.05	4.42	4.92	5.55	3.56	ns
LVTTTL_F16	1.31	1.42	1.64	1.51	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns
LVTTTL_F24	1.31	1.42	1.64	1.51	2.41	2.64	2.89	2.94	3.17	3.50	3.88	3.45	ns
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	0.83	1.36	1.47	1.55	1.58	2.12	2.33	2.54	2.09	ns
MINI_LVDS_25	0.68	0.70	0.79	0.83	1.36	1.47	1.55	1.59	2.12	2.33	2.54	2.11	ns
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.83	2.02	2.20	2.16	2.59	2.88	3.19	2.67	ns
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	0.83	1.36	1.48	1.55	1.59	2.12	2.34	2.54	2.11	ns
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.36	1.49	1.58	1.59	2.12	2.35	2.57	2.11	ns
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	0.83	1.43	1.54	1.60	1.70	2.19	2.40	2.59	2.22	ns
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	1.50	2.71	3.08	3.52	3.42	3.47	3.94	4.51	3.94	ns
HSUL_12	0.63	0.64	0.71	0.79	2.06	2.31	2.59	2.13	2.82	3.17	3.58	2.64	ns
DIFF_HSUL_12	0.58	0.61	0.70	0.81	1.83	2.04	2.26	1.92	2.59	2.90	3.25	2.44	ns
HSTL_I_S	0.61	0.64	0.73	0.79	1.55	1.69	1.80	1.91	2.31	2.55	2.79	2.42	ns
HSTL_II_S	0.61	0.64	0.73	0.78	1.21	1.34	1.43	1.70	1.97	2.20	2.42	2.22	ns
HSTL_I_18_S	0.64	0.67	0.76	0.79	1.28	1.39	1.45	1.58	2.04	2.25	2.44	2.09	ns
HSTL_II_18_S	0.64	0.67	0.76	0.79	1.18	1.31	1.40	1.69	1.94	2.17	2.39	2.20	ns
DIFF_HSTL_I_S	0.63	0.67	0.77	0.78	1.42	1.54	1.61	1.84	2.18	2.40	2.60	2.36	ns
DIFF_HSTL_II_S	0.63	0.67	0.77	0.79	1.15	1.24	1.27	1.78	1.91	2.10	2.26	2.30	ns
DIFF_HSTL_I_18_S	0.65	0.69	0.78	0.79	1.27	1.38	1.43	1.67	2.03	2.24	2.42	2.19	ns
DIFF_HSTL_II_18_S	0.65	0.69	0.78	0.81	1.14	1.23	1.26	1.72	1.90	2.09	2.25	2.23	ns

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
SSTL18_I_F	0.68	0.72	0.82	0.86	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
SSTL18_II_F	0.68	0.72	0.82	0.87	0.97	1.09	1.16	1.36	1.61	1.84	1.99	1.98	ns
SSTL18_I_DCI_F	0.68	0.72	0.82	0.76	0.89	1.02	1.10	1.30	1.53	1.77	1.92	1.91	ns
SSTL18_II_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.24	1.53	1.77	1.92	1.85	ns
SSTL18_II_T_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.27	1.53	1.77	1.92	1.88	ns
SSTL15_F	0.68	0.72	0.82	0.81	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
SSTL15_DCI_F	0.68	0.72	0.82	0.78	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL15_T_DCI_F	0.68	0.72	0.82	0.80	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL135_F	0.69	0.72	0.82	0.89	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_T_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL12_F	0.69	0.72	0.82	0.95	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
SSTL12_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
SSTL12_T_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.26	1.54	1.79	1.93	1.87	ns
DIFF_SSTL18_I_F	0.75	0.79	0.92	0.89	0.94	1.06	1.15	1.38	1.58	1.82	1.97	1.99	ns
DIFF_SSTL18_II_F	0.75	0.79	0.92	0.89	0.97	1.09	1.16	1.40	1.61	1.84	1.99	2.01	ns
DIFF_SSTL18_I_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.36	1.53	1.77	1.92	1.98	ns
DIFF_SSTL18_II_DCI_F	0.75	0.79	0.92	0.75	0.89	1.02	1.10	1.32	1.53	1.77	1.92	1.93	ns
DIFF_SSTL18_II_T_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.38	1.53	1.77	1.92	1.99	ns
DIFF_SSTL15_F	0.68	0.72	0.82	0.89	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
DIFF_SSTL15_DCI_F	0.68	0.72	0.82	0.75	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
DIFF_SSTL15_T_DCI_F	0.68	0.72	0.82	0.76	0.89	1.01	1.09	1.35	1.53	1.77	1.91	1.96	ns
DIFF_SSTL135_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_T_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.35	1.52	1.76	1.90	1.96	ns
DIFF_SSTL12_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
DIFF_SSTL12_DCI_F	0.69	0.72	0.82	0.78	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
DIFF_SSTL12_T_DCI_F	0.69	0.72	0.82	0.80	0.91	1.03	1.11	1.33	1.54	1.79	1.93	1.94	ns

Notes:

1. This I/O standard is only available in the 1.8V high-performance (HP) banks.

Table 21 specifies the values of T_{IOTPHZ} and $T_{IOIBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOIBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HP I/O banks, the internal DCI termination turn-off time is always faster than T_{IOTPHZ} when the DCITERMDISABLE pin is used. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 21: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{IOTPHZ}	T input to pad high-impedance	0.76	0.86	0.99	0.62	ns
$T_{IOIBUFDISABLE_HR}$	IBUF turn-on time from IBUFDISABLE to O output for HR I/O banks	1.72	1.89	2.14	2.17	ns
$T_{IOIBUFDISABLE_HP}$	IBUF turn-on time from IBUFDISABLE to O output for HP I/O banks	1.31	1.46	1.76	1.86	ns

Table 23: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{ODCK} /T _{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/−0.13	0.50/−0.13	0.58/−0.13	0.79/−0.18	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/−0.10	ns
T _{OSRCK} /T _{OCKSR}	SR pin Setup/Hold with respect to CLK	0.32/0.18	0.38/0.18	0.70/0.18	0.62/−0.04	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.49/−0.16	0.56/−0.16	0.68/−0.16	0.67/−0.18	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/−0.10	ns
Combinatorial						
T _{ODQ}	D1 to OQ out or T1 to TQ out	0.73	0.81	0.97	1.18	ns
Sequential Delays						
T _{OCKQ}	CLK to OQ/TQ out	0.41	0.43	0.49	0.63	ns
T _{RQ_OLOGICE2}	SR pin to OQ/TQ out (HP I/O banks only)	0.63	0.70	0.83	1.12	ns
T _{GSRQ_OLOGICE2}	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
T _{RQ_OLOGICE3}	SR pin to OQ/TQ out (HR I/O banks only)	0.63	0.70	0.83	1.12	ns
T _{GSRQ_OLOGICE3}	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
T _{RPW_OLOGICE2}	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.54	0.63	0.68	ns, Min
T _{RPW_OLOGICE3}	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.54	0.63	0.68	ns, Min

Output Serializer/Deserializer Switching Characteristics

Table 25: OSERDES Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	0.44/−0.24	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	0.49/−0.15	0.56/−0.15	0.68/−0.15	0.67/−0.25	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input Setup/Hold with respect to CLKDIV	0.27/−0.15	0.30/−0.15	0.34/−0.15	0.46/−0.25	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/−0.15	ns
T _{OSCCK_S}	SR (Reset) input Setup with respect to CLKDIV	0.41	0.46	0.75	0.70	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/−0.15	ns
Sequential Delays						
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	0.54	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	0.63	ns
Combinatorial						
T _{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	1.18	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Input/Output Delay Switching Characteristics

Table 26: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.22	3.22	3.22	3.22	µs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.00 ⁽¹⁾	200.00	200.00	200.00	200.00	MHz
	Attribute REFCLK frequency = 300.00 ⁽¹⁾	300.00	300.00	N/A	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	52.00	52.00	52.00	52.00	ns
IDELAY/ODELAY						
T _{IDELAYRESOLUTION}	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT} and T _{ODELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX} / T _{ODELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY/ODELAY	800.00	800.00	710.00	710.00	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin Setup/Hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	0.14/0.16	ns
T _{ODCCK_CE} / T _{ODCKC_CE}	CE pin Setup/Hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	0.28/0.06	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin Setup/Hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	0.10/0.23	ns
T _{ODCCK_INC} / T _{ODCKC_INC}	INC pin Setup/Hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	0.19/0.16	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin Setup/Hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	0.22/0.19	ns
T _{ODCCK_RST} / T _{ODCKC_RST}	RST pin Setup/Hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	0.32/0.11	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{ODDO_ODATAIN}	Propagation delay through ODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See TRACE report for actual values.

Table 31: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{RCKK_RSTRAM}/T_{RCKC_RSTRAM}$	Synchronous RSTRAM input	0.27/0.35	0.29/0.37	0.31/0.39	0.34/0.40	ns, Min
$T_{RCKK_WEA}/T_{RCKC_WEA}$	Write Enable (WE) input (Block RAM only)	0.38/0.15	0.41/0.16	0.46/0.17	0.54/0.19	ns, Min
$T_{RCKK_WREN}/T_{RCKC_WREN}$	WREN FIFO inputs	0.39/0.25	0.39/0.30	0.40/0.37	0.65/0.37	ns, Min
$T_{RCKK_RDEN}/T_{RCKC_RDEN}$	RDEN FIFO inputs	0.36/0.26	0.36/0.30	0.37/0.37	0.60/0.38	ns, Min
Reset Delays						
T_{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.76	0.83	0.93	1.06	ns, Max
$T_{RREC_RST}/T_{RREM_RST}$	FIFO reset recovery and removal timing ⁽¹¹⁾	1.59/–0.68	1.76/–0.68	2.01/–0.68	2.07/–0.60	ns, Max
Maximum Frequency						
$F_{MAX_BRAM_WF_NC}$	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	372.44	MHz
$F_{MAX_BRAM_RF_PERFORMANCE}$	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	372.44	MHz
$F_{MAX_BRAM_RF_DELAYED_WRITE}$	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	317.36	MHz
$F_{MAX_CAS_WF_NC}$	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	322.48	MHz
$F_{MAX_CAS_RF_PERFORMANCE}$	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	322.48	MHz
$F_{MAX_CAS_RF_DELAYED_WRITE}$	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.27	427.35	350.88	267.38	MHz
F_{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	372.44	MHz
F_{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	254.13	MHz

Notes:

- TRACE will report all of these parameters as T_{RCKO_DO} .
- T_{RCKO_DOR} includes T_{RCKO_DOW} , T_{RCKO_DOPR} , and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
- These parameters also apply to synchronous FIFO with $DO_REG = 0$.
- T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
- These parameters also apply to multirate (asynchronous) and synchronous FIFO with $DO_REG = 1$.
- T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY} , T_{RCKO_AFULL} , T_{RCKO_EMPTY} , T_{RCKO_FULL} , T_{RCKO_RDERR} , T_{RCKO_WRERR} .
- $T_{RCKO_POINTERS}$ includes both $T_{RCKO_RDCOUNT}$ and $T_{RCKO_WRCOUNT}$.
- The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
- These parameters include both A and B inputs as well as the parity inputs of A and B.
- T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
- RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Clock to Outs from Pipeline Register Clock to Output Pins						
T_DSPCKO_P_MREG	CLK MREG to P output	1.42	1.64	1.96	2.31	ns
T_DSPCKO_CARRYCASCOUT_MREG	CLK MREG to CARRYCASCOUT output	1.63	1.87	2.24	2.65	ns
T_DSPCKO_P_ADREG_MULT	CLK ADREG to P output using multiplier	2.30	2.63	3.13	3.90	ns
T_DSPCKO_CARRYCASCOUT_ADREG_MULT	CLK ADREG to CARRYCASCOUT output using multiplier	2.51	2.87	3.41	4.23	ns
Clock to Outs from Input Register Clock to Output Pins						
T_DSPCKO_P_AREG_MULT	CLK AREG to P output using multiplier	3.34	3.83	4.55	5.80	ns
T_DSPCKO_P_BREG	CLK BREG to P output not using multiplier	1.39	1.59	1.88	2.24	ns
T_DSPCKO_P_CREG	CLK CREG to P output not using multiplier	1.43	1.64	1.95	2.32	ns
T_DSPCKO_P_DREG_MULT	CLK DREG to P output using multiplier	3.32	3.80	4.51	5.74	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
T_DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}	CLK (ACOUT, BCOUT) to {A,B} register output	0.55	0.62	0.74	0.87	ns
T_DSPCKO_CARRYCASCOUT_{AREG, BREG}_MULT	CLK (AREG, BREG) to CARRYCASCOUT output using multiplier	3.55	4.06	4.84	6.13	ns
T_DSPCKO_CARRYCASCOUT_BREG	CLK BREG to CARRYCASCOUT output not using multiplier	1.60	1.82	2.16	2.58	ns
T_DSPCKO_CARRYCASCOUT_DREG_MULT	CLK DREG to CARRYCASCOUT output using multiplier	3.52	4.03	4.79	6.07	ns
T_DSPCKO_CARRYCASCOUT_CREG	CLK CREG to CARRYCASCOUT output	1.64	1.88	2.23	2.65	ns
Maximum Frequency						
F_MAX	With all registers used	741.84	650.20	547.95	429.37	MHz
F_MAX_PATDET	With pattern detector	627.35	549.75	463.61	365.90	MHz
F_MAX_MULT_NOMREG	Two register multiply without MREG	412.20	360.75	303.77	248.32	MHz
F_MAX_MULT_NOMREG_PATDET	Two register multiply without MREG with pattern detect	374.25	327.65	276.01	225.73	MHz
F_MAX_PREADD_MULT_NOADREG	Without ADREG	468.82	408.66	342.70	263.44	MHz
F_MAX_PREADD_MULT_NOADREG_PATDET	Without ADREG with pattern detect	468.82	408.66	342.70	263.44	MHz
F_MAX_NOPIPELINEREG	Without pipeline registers (MREG, ADREG)	306.84	267.81	225.02	177.15	MHz
F_MAX_NOPIPELINEREG_PATDET	Without pipeline registers (MREG, ADREG) with pattern detect	285.23	249.13	209.38	165.32	MHz

Table 38: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{\text{MMCM DCK_DEN}}/$ $T_{\text{MMCMCKD_DEN}}$	DEN Setup/Hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
$T_{\text{MMCM DCK_DWE}}/$ $T_{\text{MMCMCKD_DWE}}$	DWE Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
$T_{\text{MMCMCKO_DRDY}}$	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{\text{VCO}}/128$ assuming output duty cycle is 50%.
6. When $\text{CLKOUT4_CASCADE} = \text{TRUE}$, $\text{MMCM_F}_{\text{OUTMIN}}$ is 0.036 MHz.

PLL Switching Characteristics

Table 39: PLL Specification

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$\text{PLL_F}_{\text{INMAX}}$	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
$\text{PLL_F}_{\text{INMIN}}$	Minimum Input Clock Frequency	19.00	19.00	19.00	19.00	MHz
$\text{PLL_F}_{\text{INJITTER}}$	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
$\text{PLL_F}_{\text{INDUTY}}$	Allowable Input Duty Cycle: 19—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
$\text{PLL_F}_{\text{VCOMIN}}$	Minimum PLL VCO Frequency	800.00	800.00	800.00	800.00	MHz
$\text{PLL_F}_{\text{VCOMAX}}$	Maximum PLL VCO Frequency	2133.00	1866.00	1600.00	1600.00	MHz
$\text{PLL_F}_{\text{BANDWIDTH}}$	Low PLL Bandwidth at Typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High PLL Bandwidth at Typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
$\text{PLL_T}_{\text{STATPHAOFFSET}}$	Static Phase Offset of the PLL Outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
$\text{PLL_T}_{\text{OUTJITTER}}$	PLL Output Jitter	Note 3				
$\text{PLL_T}_{\text{OUTDUTY}}$	PLL Output Clock Duty Cycle Precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
$\text{PLL_T}_{\text{LOCKMAX}}$	PLL Maximum Lock Time	100	100	100	100	μs
$\text{PLL_F}_{\text{OUTMAX}}$	PLL Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
$\text{PLL_F}_{\text{OUTMIN}}$	PLL Minimum Output Frequency ⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
$\text{PLL_T}_{\text{EXTFDVAR}}$	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
$\text{PLL_RST}_{\text{MINPULSE}}$	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns

Table 47: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard.(1)							
T _{PSPLLCC} / T _{PHPLLCC}	No Delay clock-capable clock input and IFF(2) with PLL	XC7K70T	2.75/−0.32	3.04/−0.32	3.33/−0.32	2.42/−0.54	ns
		XC7K160T	2.85/−0.31	3.16/−0.31	3.46/−0.31	2.59/−0.56	ns
		XC7K325T	2.91/−0.27	3.24/−0.27	3.54/−0.27	2.80/−0.56	ns
		XC7K355T	2.79/−0.27	3.12/−0.27	3.40/−0.27	2.67/−0.52	ns
		XC7K410T	2.91/−0.27	3.24/−0.27	3.53/−0.27	2.78/−0.56	ns
		XC7K420T	2.83/−0.20	3.12/−0.20	3.41/−0.20	2.61/−0.50	ns
		XC7K480T	2.83/−0.20	3.12/−0.20	3.41/−0.20	2.61/−0.50	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock for HR I/O banks	−0.36/1.36	−0.36/1.50	−0.36/1.70	−0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	−0.34/1.39	−0.34/1.53	−0.34/1.73	−0.44/1.87	ns

Table 49: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	0.51	0.56	0.61	0.56	ns
T _{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	0.30	0.35	0.40	0.35	ns

Notes:

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC output specifications of the GTX transceivers in Kintex-7 FPGAs. Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further details.

Table 51: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage.	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R_{OUT}	Differential output resistance		–	100	–	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV_{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–200	–	$V_{MGTAVTT}$	mV
V_{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–	$2/3 V_{MGTAVTT}$	–	mV
R_{IN}	Differential input resistance		–	100	–	Ω
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

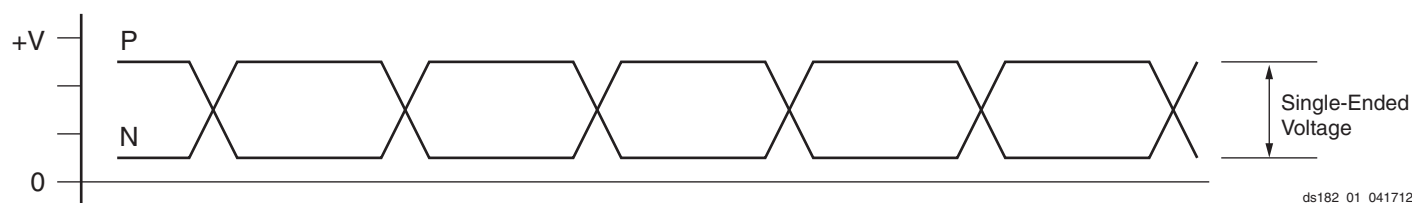


Figure 1: Single-Ended Peak-to-Peak Voltage

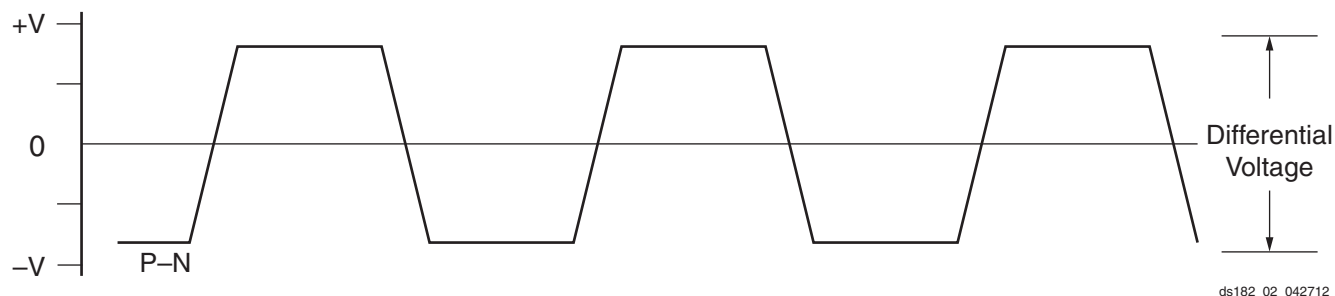


Figure 2: Differential Peak-to-Peak Voltage

Table 52 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further details.

Table 52: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V _{IDIFF}	Differential peak-to-peak input voltage	250	–	2000	mV
R _{IN}	Differential input resistance	–	100	–	Ω
C _{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTX Transceiver Switching Characteristics

Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further information.

Table 53: GTX Transceiver Performance

Symbol	Description	Output Divider	Speed Grade								Units
			1.0V						0.9V		
			-3		-2/-2L		-1 ⁽¹⁾		-2L ⁽²⁾		
			Package Type								
			FF	FB	FF	FB	FF	FB	FF	FB	
F _{GTXMAX} ⁽³⁾	Maximum GTX transceiver data rate		12.5	6.6	10.3125	6.6	8.0	6.6	6.6	6.6	Gb/s
F _{GTXMIN} ⁽³⁾	Minimum GTX transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s
F _{GTXCRANGE}	CPLL line rate range	1	3.2–6.6								Gb/s
		2	1.6–3.3								Gb/s
		4	0.8–1.65								Gb/s
		8	0.5–0.825								Gb/s
		16	N/A								Gb/s
F _{GTXQRANGE1}	QPLL line rate range 1	1	5.93– 8.0	5.93– 6.6	5.93– 8.0	5.93– 6.6	5.93– 8.0	5.93– 6.6	5.93–6.6		Gb/s
		2	2.965–4.0		2.965–4.0		2.965–4.0		2.965–3.3		Gb/s
		4	1.4825–2.0		1.4825–2.0		1.4825–2.0		1.4825–1.65		Gb/s
		8	0.74125–1.0		0.74125–1.0		0.74125–1.0		0.74125–0.825		Gb/s
		16	N/A		N/A		N/A		N/A		Gb/s
F _{GTXQRANGE2}	QPLL line rate range 2 ⁽⁴⁾	1	9.8– 12.5	N/A	9.8– 10.3125	N/A	N/A		N/A		Gb/s
		2	4.9–6.25		4.9–5.15625		N/A		N/A		Gb/s
		4	2.45–3.125		2.45–2.578125		N/A		N/A		Gb/s
		8	1.225–1.5625		1.225–1.2890625		N/A		N/A		Gb/s
		16	0.6125–0.78125		0.6125– 0.64453125		N/A		N/A		Gb/s
F _{GCPLLRANGE}	GTX transceiver CPLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz
F _{GQPLLRange1}	GTX transceiver QPLL frequency range 1		5.93–8.0		5.93–8.0		5.93–8.0		5.93–6.6		GHz

Table 53: GTX Transceiver Performance (Cont'd)

Symbol	Description	Output Divider	Speed Grade								Units
			1.0V						0.9V		
			-3		-2/-2L		-1 ⁽¹⁾		-2L ⁽²⁾		
			Package Type								
			FF	FB	FF	FB	FF	FB	FF	FB	
F _{GQPLL} RANGE2	GTX transceiver QPLL frequency range 2		9.8–12.5		9.8–10.3125		N/A		N/A		GHz

Notes:

1. The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s.
2. The -2L (0.9V) speed grade requires a 4-byte internal data width for operation above 3.8 Gb/s.
3. Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
4. For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
F _{GTXDRPCLK}	GTXDRPCLK maximum frequency	175.01	175.01	156.25	125.00	MHz

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F _{GCLK}	Reference clock frequency range	-3 speed grade	60	–	700	MHz
		All other speed grades	60	–	670	MHz
T _{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T _{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T _{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

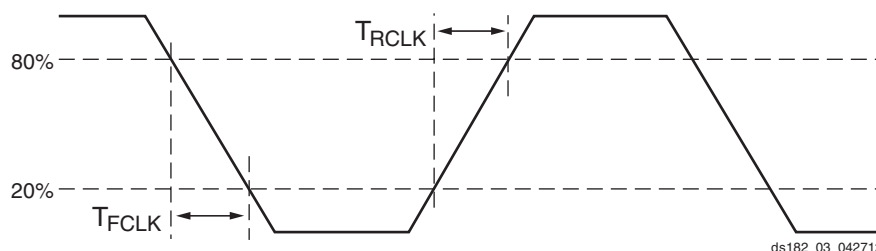


Figure 3: Reference Clock Timing Parameters

XADC Specifications

Table 67: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
V _{CCADC} = 1.8V ± 5%, V _{REFP} = 1.25V, V _{REFN} = 0V, ADCCLK = 26 MHz, T _j = −40°C to 100°C, Typical values at T _j =+40°C						
ADC Accuracy ⁽¹⁾						
Resolution			12	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±3	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	LSBs
Offset Error		Offset calibration enabled	–	–	±6	LSBs
Gain Error		Gain calibration disabled	–	–	±0.5	%
Offset Matching		Offset calibration enabled	–	–	4	LSBs
Gain Matching		Gain calibration disabled	–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio ⁽²⁾	SNR	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion ⁽²⁾	THD	F _{SAMPLE} = 500KS/s, F _{IN} = 20KHz	–	70	–	dB
ADC Accuracy at Extended Temperatures (-55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	±1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	
Analog Inputs ⁽³⁾						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	−0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	−0.1	–	V _{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		T _j = −40°C to 100°C.	–	–	±4	°C
		T _j = −55°C to +125°C	–	–	±6	°C
Supply Sensor Error		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −40°C to +100°C	–	–	±1	%
		Measurement range of V _{CCAUX} 1.8V ±5% T _j = −55°C to +125°C	–	–	±2	%
Conversion Rate ⁽⁴⁾						
Conversion Time - Continuous	t _{CONV}	Number of ADCCLK cycles	26	–	32	Cycles
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	Cycles
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz
DCLK Duty Cycle			40	–	60	%

Table 67: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference⁽⁵⁾						
External Reference	V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V_{REFP} pin to AGND, $T_j = -40^{\circ}\text{C}$ to 100°C	1.2375	1.25	1.2625	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for new BitGen option XADCEnhancedLinearity = ON.
- See the ADC chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- See the Timing chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- Any variation in the reference voltage from the nominal $V_{REFP} = 1.25\text{V}$ and $V_{REFN} = 0\text{V}$ will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by $\pm 4\%$ is permitted. On-chip reference variation is $\pm 1\%$.

Configuration Switching Characteristics

Table 68: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width	250	250	250	250	ns, Min
CCLK Output (Master Mode)						
T _{ICCK}	Master CCLK output delay	150	150	150	150	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F _{MCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F _{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T _{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T _{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F _{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2)	100.00	100.00	100.00	70.00	MHz, Max